

I. Power section 1 * SKiiP803GB061CT per phase

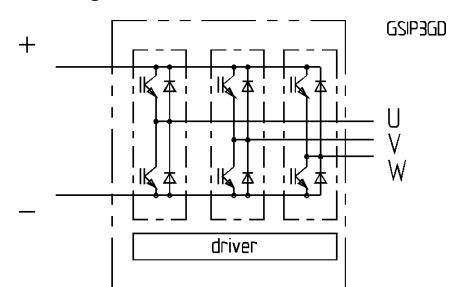
Absolute maximum ratings		Values	Units
Symbol	Conditions ¹⁾		
IGBT and inverse diode			
V_{CES}		600	V
V_{CC}	Operating DC link voltage	400	V
V_{GES}		± 20	V
I_c	IGBT, $T_{heat\ sink} = 25 / 70\ ^\circ C$	800 / 600	A
I_{CM}	IGBT, $t_p < 1\ ms, T_{heat\ sink} = 25^\circ C$	1600	A
I_F	Diode, $T_{heat\ sink} = 25 / 70\ ^\circ C$	800 / 600	A
I_{FM}	Diode, $t_p < 1\ ms$	1200	A
I_{FSM}	Diode, $T_j = 150\ ^\circ C, 10ms$; sin	6000	A
I^2t (Diode)	Diode, $T_j = 150\ ^\circ C, 10ms$	180	kA ² s
$T_j, (T_{stg})$		-40...+150 (125)	°C
V_{isol}	AC, 1min.	2500	V
$I_{C-package}$ ⁴⁾	$T_{heat\ sink} = 70^\circ C, T_{term} = 115^\circ C$	1 * 500	A

Characteristics		min.	typ.	max.	Units
Symbol	Conditions ¹⁾				
IGBT					
$V_{(BR)CES}$	gate driver without supply	$\geq V_{CES}$	—	—	V
I_{CES}	$V_{GE} = 0, T_j = 25\ ^\circ C$	—	1,2	—	mA
V_{CE} ⁷⁾	$V_{CE} = V_{CES}, T_j = 125\ ^\circ C$	—	36	—	mA
V_{CEO} ⁷⁾	$T_j = 125\ ^\circ C$	—	0,9	—	V
r_T ⁷⁾	$T_j = 125\ ^\circ C$	—	2,54	—	mΩ
V_{CESat} ⁷⁾	$I_C = 560A, T_j = 125\ ^\circ C$	—	2,3	—	V
V_{CESat} ⁷⁾	$I_C = 560A, T_j = 25\ ^\circ C$	—	—	2,2	V
$E_{on} + E_{off}$ ⁵⁾	$I_C=560A, V_{CC}=300V$	50	—	—	mJ
	$T_j = 125\ ^\circ C$	—	71	—	mJ
C	per SKiiP, AC side	—	1	—	nF
L_{CE}	top, bottom	—	10	—	nH
$R_{CC'-EE'}$	resistance, terminal-chip	—	0,40	—	mΩ
Inverse diode ²⁾					
$V_F = V_{EC}$	$I_F = 600A; T_j = 125\ ^\circ C$	—	1,5	—	V
$V_F = V_{EC}$	$I_F = 600A; T_j = 25\ ^\circ C$	—	—	1,7	V
$E_{on} + E_{off}$ ⁵⁾	$I_F = 600A; T_j = 125\ ^\circ C$	—	18	—	mJ
V_{TO}	$T_j = 125\ ^\circ C$	—	0,9	—	V
r_T	$T_j = 125\ ^\circ C$	—	1,00	—	mΩ
Thermal characteristics					
R_{thjs}	per IGBT	—	—	0,047	°C/W
R_{thjs}	per diode	—	—	0,092	°C/W
R_{thsa} ³⁾	L: P16 heat sink; 280 m ³ / h	—	—	0,033	°C/W
	W: WK 40; 8l/min; 50% glycol	—	—	0,010	°C/W
Current sensor					
I_p RMS	$T_a=100\ ^\circ C, V_{supply} = \pm 15V$	—	1 * 400	—	A
I_{pmax} RMS	$t \leq 2\ s$	—	1 * 500	—	A
Linearity	$V_{supply} \geq \pm 14,25V, 0 \leq I \leq \pm 700A$, per sensor	—	0,1	—	%
I_{peak}	$t \leq 10\ \mu s$, per sensor	—	± 3000	—	A
Mechanical data					
M1	DC terminals, SI Units	4	—	6	Nm
M2	AC terminals, SI Units	8	—	10	Nm
M3	to heat sink ⁶⁾	—	3	—	Nm

SKiiPPACK®**SK integrated intelligent Power PACK****3rd Generation
6-pack****SKiiP 803GD061-3DUW ³⁾**

Target data

housing S33

**Features**

- SKiiP technology inside
 - pressure contact of ceramic to heat sink; low thermal impedance
 - pressure contact of main electric terminals
 - pressure contact of auxiliary electric terminals
 - increased thermal cycling capability
 - low stray inductance
 - homogenous current distribution
- integrated current sensor
- integrated temperature sensor
- high power density

¹⁾ $T_{heatsink} = 25\ ^\circ C$, unless otherwise specified²⁾ CAL = Controlled Axial Lifetime Technology (soft and fast)³⁾ D integrated gate driver

U with DC-bus voltage measurement (option for GB)

L mounted on standard P16 for forced air cooling

W mounted on standard water cooler

⁴⁾ $T_{term} =$ temperature of terminal with SKiiPPACK 3rd generation gate driver⁵⁾ with SKiiPPACK 3rd generation gate driver⁶⁾ assembly instruction must be followed⁷⁾ measured at chip level⁸⁾ external paralleling necessary

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